Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 250847US2X	SERIAL NO. 10/810,713 ~~New Application~~
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Sotoshi YAMADA, et al.	
		FILING DATE Herewith	GROUP 2862

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	TRANSLATION NO
JMB	AF	7-83884	03/31/95	Japan (with English Abstract)		x
	AG	9-189682	07/22/97	Japan (with English Abstract)		x
	AH	11-248685	09/17/99	Japan (with English Abstract)		x
↓	AI	2002-90490	03/27/02	Japan (with English Abstract)		x
	AJ					
	AK					
	AL					
	AM					

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JMB	AN	Y. KATAOKA, et al. "Application of GMR Line Sensor to Eddy Current Testing Probe", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 27, No. 4, pp. 385-388, April 1, 2003
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	AW	

☐ Additional References sheet(s) attached

Examiner Jaeyoung Kahdr — Date Considered 11/8/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.